FuTuRe 2019 - Workshop on the Future of Silicon Detector Technologies

Report of Contributions

Contribution ID: **1**   Type: **not specified**

Arrival and Registration

Monday 2 December 2019 08:30 (30 minutes)

Contribution ID: **2** Type: **not specified**

Welcome address

Monday 2 December 2019 09:00 (10 minutes)

Presenter: Prof. ORTLEPP, Thomas (CiS)

Contribution ID: **3**   Type: **not specified**

Coffee Break

Contribution ID: **4**   Type: **not specified**

Lunch Break

Contribution ID: **5**   Type: **not specified**

Coffee Break

Contribution ID: **6**   Type: **not specified**

Coffee Break

Contribution ID: **7**   Type: **not specified**

Workshop Dinner

Contribution ID: **8**   Type: **not specified**

Lunch Break

Contribution ID: **9** Type: **not specified**

Coffee Break

Contribution ID: **10**   Type: **not specified**

End of the workshop

Tuesday 3 December 2019 16:30 (30 minutes)

Contribution ID: **11** Type: **not specified**

Arrival and Registration

Tuesday 3 December 2019 08:30 (30 minutes)

Contribution ID: **12**   Type: **not specified**

Introduction of SiDE Business Unit of CiS

Monday 2 December 2019 09:10 (30 minutes)

Presenter: RODER, Ralf Mario (CIS Institut fuer Mikrosensorik GmbH (DE))

Contribution ID: **13** Type: **not specified**

tbd

Monday 2 December 2019 09:40 (30 minutes)

Presenter: Prof. YOSHIKAWA, Nobuyuki (Yokohama National University)

Session Classification: Readout Electronics

Contribution ID: **14**   Type: **not specified**

tbd

Monday 2 December 2019 10:10 (30 minutes)

Presenter: Mr HIRONAKA, Yoshi (Yokohama National University)

Session Classification: Readout Electronics

Contribution ID: **15** Type: **not specified**

Superconducting NbN Hot-Electron Bolometer as a Fast Diagnostic Tool for Accelerator Light Sources: System and Readout Design

Monday 2 December 2019 11:15 (30 minutes)

Presenter: Mr SCHMID, Alexander (Karlsruhe Institut für Technologie)

Session Classification: Readout Electronics

Contribution ID: **16** Type: **not specified**

tbd

Monday 2 December 2019 11:45 (30 minutes)

Presenter: Prof. ORTLEPP, Thomas (CiS)

Session Classification: Readout Electronics

Contribution ID: **17**   Type: **not specified**

Introduction to Processes and Workflow in Radiation Oncology

Monday 2 December 2019 13:30 (30 minutes)

Presenter: Mr SCHILZ, Johannes (Strahlenschutzseminar in Thüringen e.V.)

Session Classification: Dosimetry in Radiation Therapy

Contribution ID: **18** Type: **not specified**

tbd

Monday 2 December 2019 14:00 (30 minutes)

Presenter: Mr KRANZER, Rafael (PTW Freiburg)

Session Classification: Dosimetry in Radiation Therapy

Contribution ID: 19 Type: **not specified**

tbd

Monday 2 December 2019 14:30 (30 minutes)

Presenter: Mrs SCHADE, Stephanie (Technische Hochschule Mittelhessen)

Session Classification: Dosimetry in Radiation Therapy

Contribution ID: **20**   Type: **not specified**

Semiconductor-based detectors for dosimetry in radiation therapy

Monday 2 December 2019 15:30 (30 minutes)

Presenter: Prof. KRAUTSCHNEIDER, Wolfgang (TU Hamburg)

Session Classification: Dosimetry in Radiation Therapy

Contribution ID: **21**   Type: **not specified**

From detectors for proton cancer therapy to atomic defect characterizations with positrons

Monday 2 December 2019 16:00 (30 minutes)

Presenter: Dr WAGNER, Andreas (HZDR Nuclear Physics Division)

Session Classification: Dosimetry in Radiation Therapy

Contribution ID: **22**   Type: **not specified**

Detector Development for Photon Science at PSI

Tuesday 3 December 2019 09:00 (30 minutes)

Presenter: SCHMITT, Bernd (Paul Scherrer Institut)

Session Classification: Sensor Development for X-Rays

Contribution ID: **23**   Type: **not specified**

Towards soft X-ray detection using LGAD sensors

Tuesday 3 December 2019 09:30 (30 minutes)

Presenter: ZHANG, Jiaguo (Paul Scherrer Institut)

Session Classification: Sensor Development for X-Rays

Contribution ID: **24** Type: **not specified**

tbd

Tuesday 3 December 2019 10:30 (30 minutes)

Presenter: CORREA MAGDALENA, Jonathan (Deutsches Elektronen-Synchrotron DESY)

Session Classification: Sensor Development for X-Rays

Contribution ID: 25   Type: **not specified**

Doping Profiles for Shallow Junctions

Tuesday 3 December 2019 11:00 (30 minutes)

Presenter: WITTIG, Tobias (CIS Institut fuer Mikrosensorik GmbH (DE))

Session Classification: Sensor Development for X-Rays

Contribution ID: **26**   Type: **not specified**

Discussion

Tuesday 3 December 2019 11:30 (30 minutes)

Session Classification: Sensor Development for X-Rays

Contribution ID: **27**   Type: **not specified**

Density Functional Theory-based theory of defects

Tuesday 3 December 2019 13:00 (30 minutes)

Presenter: Prof. RUNGE, Erich (Technische Universität Ilmenau)

Session Classification: Defect Engineering

Contribution ID: **28**   Type: **not specified**

Development of Radiation Hard Silicon Detectors - The RD50 collaboration

Tuesday 3 December 2019 13:30 (30 minutes)

Presenter: MOLL, Michael (CERN)

Session Classification: Defect Engineering

Contribution ID: **29**   Type: **not specified**

Light-induced defects in silicon solar cells: a possible impact on the mainstream silicon technology

Tuesday 3 December 2019 14:00 (30 minutes)

Presenter: Mr MCHEDLIDZE, Teimuraz (TU Dresden)

Session Classification: Defect Engineering

Contribution ID: **30** Type: **not specified**

Defects in 6"Cz Si EPI-wafer

Tuesday 3 December 2019 15:00 (30 minutes)

Presenter: Mrs SEIFERT, Daniela (X-FAB Semiconductor Foundries GmbH)

Session Classification: Defect Engineering

Contribution ID: **31**   Type: **not specified**

Low gain avalanche detectors (LGAD) –Can the A_Si-Si_i defect explain their insufficient radiation hardness?

Tuesday 3 December 2019 15:30 (30 minutes)

Presenter: LAUER, Kevin (CIS Institut fuer Mikrosensorik GmbH (DE))

Session Classification: Defect Engineering

Contribution ID: **32** Type: **not specified**

Discussion

Tuesday 3 December 2019 16:00 (30 minutes)

Session Classification: Defect Engineering